

**Search Notes**

Application/Control No.

10/716,544

Examiner

Feben M. Haile

Applicant(s)/Patent under  
Reexamination

MENG, TERESA H.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner
370	328	5/2-3/2007	FH
370	332	5/2-3/2007	FH
370	465	5/2-3/2007	FH
370	318	5/2-3/2007	FH
370	468	5/2-3/2007	FH
455	522	5/2-3/2007	FH
455	69	5/2-3/2007	FH
455	452.1	5/2-3/2007	FH
455	226.2	5/2-3/2007	FH
455	115.3	5/2-3/2007	FH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search: power, rate, measur\$3, calculat\$3, determin\$3, sens\$3, adjust\$3, chang\$3, modify\$3, alter\$3, increas\$3, decreas\$3	5/2-3/2007	FH
Consulted Ian Moore	5/2/2007	FH
Consulted Ian Moore	12/5/2007	FH
Updated Search	12/5 & 7/2007	FH